

<b>Notice of References Cited</b>	Application/Control No. 10/658,620	Applicant(s)/Patent Under Reexamination LIM, CHEOL WANG	
	Examiner Daniel G. DePumpo	Art Unit 3611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,286,848 B1	09-2001	Augustin, Stephan	280/287
	B	US-6,612,598 B2	09-2003	Wu, Jung-Jyh	280/270
	C	US-6,161,847 A	12-2000	Howell et al.	280/30
	D	US-6,530,589 B1	03-2003	Ma, Pei-Chuan	280/278
	E	US-6,575,486 B2	06-2003	Ma, Pei-Chuan	280/287
	F	US-6,120,048 A	09-2000	Li, Hsing	280/270
	G	US-6,152,473 A	11-2000	Shih, Wen Fu	280/278
	H	US-6,431,567 B2	08-2002	Tsai, Shui-Te	280/87.041
	I	US-6,609,723 B2	08-2003	Chuang, A-Chueh	280/287
	J	US-4,079,957	03-1978	Bleese, Wilfred J.	280/278
	K	US-5,279,181 A	01-1994	Boudreau, Robert J.	74/551.1
	L	US-5,553,879 A	09-1996	Niemeyer et al.	280/279
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.